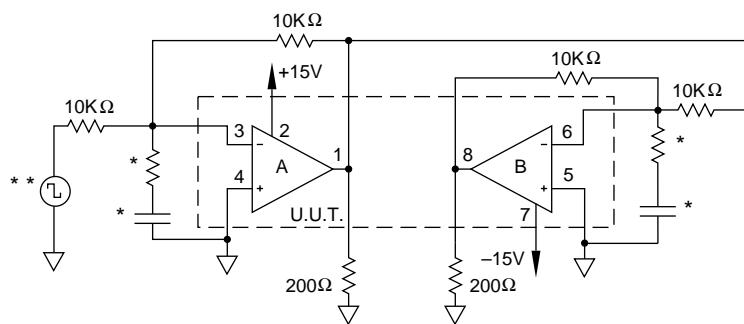


**TABLE 4 GROUP A INSPECTION**
**PA21M**

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SG	PARAMETER	SYMBOL	TEMP.	POWER	TEST CONDITIONS	MIN	MAX	UNITS
1	Quiescent Current	$I_Q$	25°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		75	mA
1	Input Offset Voltage	$V_{OS}$	25°C	$\pm 2.5$	$V_{IN} = 0, A_V = 100$		10	mV
1	Input Offset Voltage	$V_{OS}$	25°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		10	mV
1	Input Offset Voltage	$V_{OS}$	25°C	$\pm 20$	$V_{IN} = 0, A_V = 100$		14	mV
1	Input Bias Current + IN	$+I_B$	25°C	$\pm 15$	$V_{IN} = 0$		1000	nA
1	Input Bias Current -IN	$-I_B$	25°C	$\pm 15$	$V_{IN} = 0$		1000	nA
1	Input Offset Current	$I_{OS}$	25°C	$\pm 15$	$V_{IN} = 0$		500	nA
3	Quiescent Current	$I_Q$	-55°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		75	mA
3	Input Offset Voltage	$V_{OS}$	-55°C	$\pm 2.5$	$V_{IN} = 0, A_V = 100$		14	mV
3	Input Offset Voltage	$V_{OS}$	-55°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		14	mV
3	Input Offset Voltage	$V_{OS}$	-55°C	$\pm 20$	$V_{IN} = 0, A_V = 100$		18	mV
3	Input Bias Current + IN	$+I_B$	-55°C	$\pm 15$	$V_{IN} = 0$		1000	nA
3	Input Bias Current -IN	$-I_B$	-55°C	$\pm 15$	$V_{IN} = 0$		1000	nA
3	Input Offset Current	$I_{OS}$	-55°C	$\pm 15$	$V_{IN} = 0$		500	nA
2	Quiescent Current	$I_Q$	125°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		105	mA
2	Input Offset Voltage	$V_{OS}$	125°C	$\pm 2.5$	$V_{IN} = 0, A_V = 100$		15	mV
2	Input Offset Voltage	$V_{OS}$	125°C	$\pm 15$	$V_{IN} = 0, A_V = 100$		15	mV
2	Input Offset Voltage	$V_{OS}$	125°C	$\pm 20$	$V_{IN} = 0, A_V = 100$		19	mV
2	Input Bias Current + IN	$+I_B$	125°C	$\pm 15$	$V_{IN} = 0$		1000	nA
2	Input Bias Current -IN	$-I_B$	125°C	$\pm 15$	$V_{IN} = 0$		1000	nA
2	Input Offset Current	$I_{OS}$	125°C	$\pm 15$	$V_{IN} = 0$		500	nA
4	Output Voltage $I_O = 2A$	$V_O$	25°C	$\pm 9.5$	$R_L = 3\Omega$	6.0		V
4	Output Voltage $I_O = 100mA$	$V_O$	25°C	$\pm 11$	$R_L = 100\Omega$	10		V
4	Output Voltage $I_O = 1A$	$V_O$	25°C	$\pm 4.8$	$R_L = 3\Omega$	3.0		V
4	Stability/Noise	$E_N$	25°C	$\pm 15$	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1.0	mV
4	Crosstalk	XTLK	25°C	$\pm 15$	$R_L = 3\Omega$	50		dB
4	Slew Rate	SR	25°C	$\pm 15$	$R_L = 500\Omega$	.5		V/ $\mu$ S
4	Open Loop Gain	$A_{OL}$	25°C	$\pm 15$	$R_L = 500\Omega, F = 10Hz$	75		dB
4	Common-mode Rejection	CMR	25°C	$\pm 17$	$R_L = 500\Omega, V_{CM} = \pm 14V$	60		dB
6	Output Voltage $I_O = 2A$	$V_O$	-55°C	$\pm 9.5$	$R_L = 3\Omega$	6.0		V
6	Output Voltage $I_O = 100mA$	$V_O$	-55°C	$\pm 11$	$R_L = 100\Omega$	10		V
6	Output Voltage $I_O = 1A$	$V_O$	-55°C	$\pm 4.8$	$R_L = 3\Omega$	3.0		V
6	Stability/Noise	$E_N$	-55°C	$\pm 15$	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1.0	mV
6	Slew Rate	SR	-55°C	$\pm 15$	$R_L = 500\Omega$	.5		V/ $\mu$ S
6	Open Loop Gain	$A_{OL}$	-55°C	$\pm 15$	$R_L = 500\Omega, F = 10Hz$	75		dB
6	Common-mode Rejection	CMR	-55°C	$\pm 17$	$R_L = 500\Omega, V_{CM} = \pm 14V$	60		dB
5	Output Voltage $I_O = 1A$	$V_O$	125°C	$\pm 4.8$	$R_L = 3\Omega$	3.0		V
5	Output Voltage $I_O = 100mA$	$V_O$	125°C	$\pm 11$	$R_L = 100\Omega$	10.0		V
5	Output Voltage $I_O = 750mA$	$V_O$	125°C	$\pm 4.0$	$R_L = 3\Omega$	2.25		V
5	Stability/Noise	$E_N$	125°C	$\pm 15$	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1.0	mV
5	Slew Rate	SR	125°C	$\pm 15$	$R_L = 500\Omega$	.5		V/ $\mu$ S
5	Open Loop Gain	$A_{OL}$	125°C	$\pm 15$	$R_L = 500\Omega, F = 10Hz$	75		dB
5	Common-mode Rejection	CMR	125°C	$\pm 17$	$R_L = 500\Omega, V_{CM} = \pm 14V$	60		dB

**BURN IN CIRCUIT**


\* These components are used to stabilize device due to poor high frequency characteristics of burn in board.

\*\* Input signals are calculated to result in internal power dissipation of approximately 2.1W at case temperature = 125°C.